



Channel length modulation length parameter

- λ describes small dependence of drain current on V_{ds} in saturation.
- Factor is measured empirically.
- New drain current equation:

– I_d = 0.5k' (W/L)(V_{gs} - V_t) ²(l - λ V_{ds})

Equation has a discontinuity between linear and saturation regions---small enough to be ignored.

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Leakage and subthreshold current A variety of leakage currents draw current away from the main logic path.

• The subthreshold current is one particularly important type of leakage current.

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Types of leakage current

- Weak inversion current (a.k.a. subthreshold current).
- Reverse-biased pn junctions.
- Drain-induced barrier lowering.
- Gate-induced drain leakage;
- Punchthrough currents.
- Gate oxide tunneling.
- Hot carriers.

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Threshold voltage

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Components of threshold voltage V_t:

$$V_{t0} = V_{fb} + \phi_s + \frac{Q_b}{C_{ox}} + V_{II}$$

- V_{fb} = flatband voltage; depends on difference in work function between gate and substrate and on fixed surface charge.
- $\phi_s = \text{surface potential (about } 2\phi_f).$
- Voltage on parallel plate capacitor.
- Additional ion implantation. Modern VLSI Design 4c: Chapter 2





Metal interconnect

- Many layers of metal interconnect are possible.
 - 12 layers of metal are common.
- Lower layers have smaller features, higher layers have larger features.
- Can't directly go from a layer to any other layer.

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Copper interconnect

- Much better electrical characteristics.
- Copper is poisonous to semiconductors---must be isolated from silicon.
 - Bottom layer of interconnect is aluminum.

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